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U.S. UTILITY Patent Application

PATENT NUMBER and
ISSUE DATE

APPL NUM 10046346	FILING DATE 10/26/2001	CLASS 857 336	SUBCLASS 77	GAU 2832	EXAMINER W. W. W. S. O. W.
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****CONTINUING DATA VERIFIED:**

**** FOREIGN APPLICATIONS VERIFIED:**

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Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no Verified and Acknowledged Examiners's initials			
TITLE : Minimizing degradation of SiC bipolar semiconductor devices <small>U.S. DEPT. OF COMM./PAT. & TM-PTO-436 (Rev. 12-94)</small>			

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G.
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheets Drawg.	Figs. Drawg.
		Print Fig.	
<input type="checkbox"/> TERMINAL DISCLAIMER		Application Examiner	
		PREPARED FOR ISSUE	
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